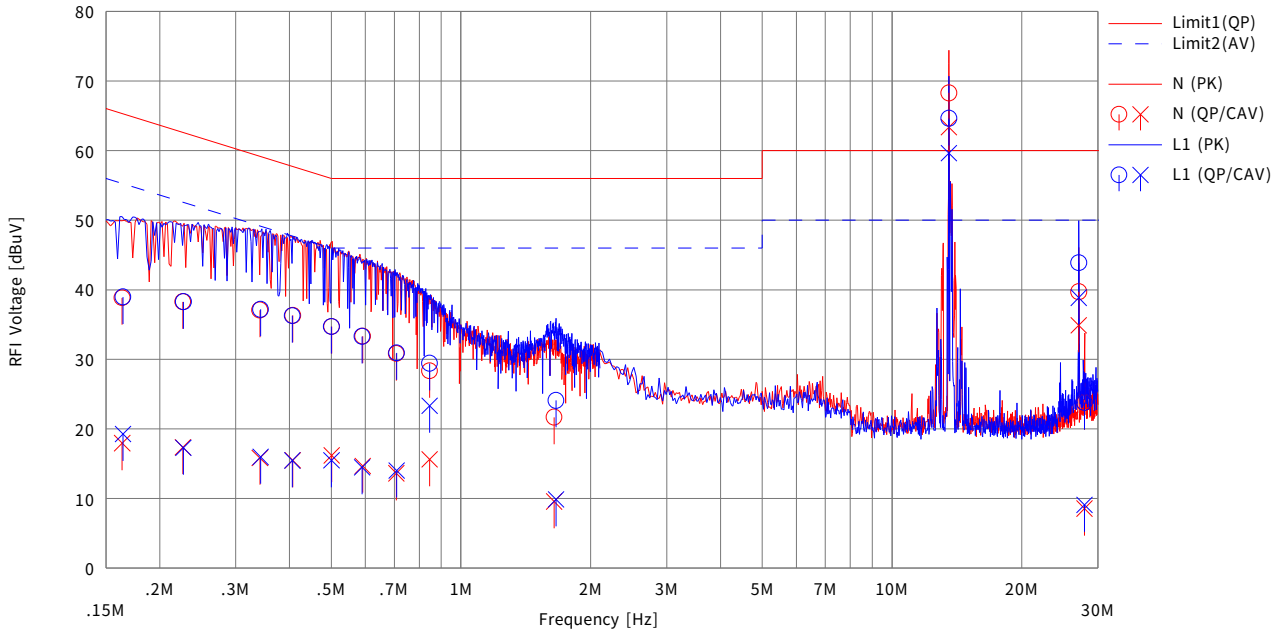
DATA OF CONDUCTED EMISSION TEST

UL Japan,Inc. Shonan EMC Lab. No.2 Shielded Room
Date : 2021/01/26

Company	: NIDEC SANKYO CORPORATION	Mode	: NFC Communication
Kind of EUT	: RFID Module	Order No.	: 13532641S
Model No.	: CLESS001	Power	: **AC 120 V / 60 Hz (DC Power Supply)**
Serial No.	: DS R-0090001	Temp./Humi.	: 22 deg.C / 30 %RH
Remarks	: with Tag, Refer to the data on the next page for the carrier frequency (13.56 MHz)		

Limit : FCC_Part 15 Subpart C(15.207)

Engineer : Yasumasa Owaki



No.	Freq.	Reading		C.Fac	Results		Limit		Margin		Phase	Comment
		<QP>	<CAV>		<QP>	<CAV>	<QP>	<AV>	<QP>	<AV>		
	[MHz]	[dBuV]	[dBuV]	[dB]	[dBuV]	[dBuV]	[dBuV]	[dBuV]	[dB]	[dB]		
1	0.16374	26.40	5.50	12.44	38.84	17.94	65.27	55.27	26.4	37.3	N	
2	0.22651	25.80	4.90	12.46	38.26	17.36	62.58	52.58	24.3	35.2	N	
3	0.34152	24.60	3.40	12.45	37.05	15.85	59.17	49.17	22.1	33.3	N	
4	0.40759	23.80	3.00	12.48	36.28	15.48	57.70	47.70	21.4	32.2	N	
5	0.50099	22.20	3.70	12.50	34.70	16.20	56.00	46.00	21.3	29.8	N	
6	0.59141	20.80	2.20	12.52	33.32	14.72	56.00	46.00	22.6	31.2	N	
7	0.70808	18.30	1.10	12.52	30.82	13.62	56.00	46.00	25.1	32.3	N	
8	0.84551	15.80	3.10	12.53	28.33	15.63	56.00	46.00	27.6	30.3	N	
9	1.64371	9.10	-3.00	12.57	21.67	9.57	56.00	46.00	34.3	36.4	N	
10	13.56000	55.00	50.10	13.26	68.26	63.36	60.00	50.00	-8.3	-13.4	N	Reference
11	27.12000	25.80	21.00	13.90	39.70	34.90	60.00	50.00	20.3	15.1	N	
12	27.96782	9.80	-5.40	13.94	23.74	8.54	60.00	50.00	36.2	41.4	N	
13	0.16425	26.50	6.80	12.46	38.96	19.26	65.25	55.25	26.2	35.9	L1	
14	0.22731	25.80	4.80	12.46	38.26	17.26	62.55	52.55	24.2	35.2	L1	
15	0.34286	24.70	3.50	12.47	37.17	15.97	59.13	49.13	21.9	33.1	L1	
16	0.40609	23.80	3.00	12.47	36.27	15.47	57.73	47.73	21.4	32.2	L1	
17	0.50059	22.20	3.00	12.49	34.69	15.49	56.00	46.00	21.3	30.5	L1	
18	0.58923	20.80	2.00	12.48	33.28	14.48	56.00	46.00	22.7	31.5	L1	
19	0.70880	18.40	1.50	12.52	30.92	14.02	56.00	46.00	25.0	31.9	L1	
20	0.84547	16.90	10.80	12.52	29.42	23.32	56.00	46.00	26.5	22.6	L1	
21	1.66070	11.50	-2.70	12.57	24.07	9.87	56.00	46.00	31.9	36.1	L1	
22	13.56000	51.50	46.50	13.11	64.61	59.61	60.00	50.00	-4.7	-9.7	L1	Reference
23	27.12000	30.40	25.40	13.46	43.86	38.86	60.00	50.00	16.1	11.1	L1	
24	27.96766	10.30	-4.40	13.49	23.79	9.09	60.00	50.00	36.2	40.9	L1	

Calculation:Result[dBuV]=Reading[dBuV]+C.Fac(LISN(AMN)+Cable+ATT)[dB]
LISN(AMN) : SLS-03

DATA OF CONDUCTED EMISSION TEST

UL Japan,Inc. Shonan EMC Lab. No.2 Shielded Room
Date : 2021/01/26

Company : NIDEC SANKYO CORPORATION
Kind of EUT : RFID Module
Model No. : CLESS001
Serial No. : DS R-0090001
Remarks : Antenna: terminated

Mode : NFC Communication
Order No. : 13532641S
Power : **AC 120 V / 60 Hz (DC Power Supply)**
Temp./Humi. : 22 deg.C / 30 %RH

Limit : FCC_Part 15 Subpart C(15.207)

Engineer : Yasumasa Owaki

<< QP/CAV DATA >>

No.	Freq.	Reading		C.Fac	Results		Limit		Margin		Phase	Comment
		<QP>	<CAV>		<QP>	<CAV>	<QP>	<AV>	<QP>	<AV>		
	[MHz]	[dBuV]	[dBuV]	[dB]	[dBuV]	[dBuV]	[dBuV]	[dBuV]	[dB]	[dB]		
1	13.56000	12.70	9.30	13.26	25.96	22.56	60.00	50.00	34.0	27.4	N	
2	13.56000	9.70	6.20	13.11	22.81	19.31	60.00	50.00	37.1	30.6	L1	

Calculation:Result[dBuV]=Reading[dBuV]+C.Fac(LISN(AMN)+Cable+ATT)[dB]
LISN(AMN) : SLS-03

Data of Electric field strength of Fundamental emission and Spurious emission within the band: FCC15.225(a)(b)(c)

UL Japan, Inc.
Shonan EMC Lab., No.1 Semi Anechoic Chamber

Company:	NIDEC SANKYO CORPORATION	Regulation:	FCC Part15 Subpart C 15.225
Equipment:	RFID Module	Test Distance:	3 m
Model:	CLESS001	Date:	January 25, 2021
Sample No.:	DS R-0090001	Temperature:	20 deg.C
Power:	DC 24 V	Humidity:	40 %RH
Mode:	NFC Communication	ENGINEER:	Yasumasa Owaki

Remarks: : without Tag, Vertical polarization (antenna angle) of the worst case: 90 deg.

Fundamental emission

No.	FREQ	Test Receiver Reading		Antenna Factor	Loss	AMP GAIN	Distance factor	RESULT		LIMIT (30m)	MARGIN	
		Hor	Ver					Hor	Ver		Hor	Ver
	[MHz]	[dBuV]	[dBuV]	[dB/m]	[dB]	[dB]	[dB]	[dBuV/m]	[dBuV/m]	[dBuV/m]	[dB]	[dB]
1	13.560	66.6	76.4	19.5	6.6	31.9	-40.0	20.9	30.7	83.9	63.0	53.2

Calculation:Result[dBuV/m]=Reading[dBuV]+Ant.Fac[dB/m]+Loss(Cable+ATT)[dB]-Gain(AMP)[dB]+Distance factor[dB]

Distance factor: 40 x log (3 m/30 m) = -40 dB

Limits (30m)

・13.553 MHz to 13.567 MHz : 83.9 dBuV/m (FCC 15.225(a))

Spurious emission within the band

No.	FREQ	Test Receiver Reading		Antenna Factor	Loss	AMP GAIN	Distance factor	RESULT		LIMIT (30m)	MARGIN	
		Hor	Ver					Hor	Ver		Hor	Ver
	[MHz]	[dBuV]	[dBuV]	[dB/m]	[dB]	[dB]	[dB]	[dBuV/m]	[dBuV/m]	[dBuV/m]	[dB]	[dB]
1	13.066	30.3	33.4	19.5	6.6	31.9	-40.0	-15.4	-12.3	29.5	44.9	41.8
2	13.110	30.1	30.4	19.5	6.6	31.9	-40.0	-15.6	-15.3	29.5	45.1	44.8
3	13.349	36.1	44.9	19.5	6.6	31.9	-40.0	-9.6	-0.8	40.5	50.1	41.3
4	13.410	34.5	43.5	19.5	6.6	31.9	-40.0	-11.2	-2.2	40.5	51.7	42.7
5	13.490	38.2	47.5	19.5	6.6	31.9	-40.0	-7.5	1.8	50.4	57.9	48.6
6	13.553	53.3	62.9	19.5	6.6	31.9	-40.0	7.6	17.2	50.4	42.8	33.2
7	13.567	51.9	61.5	19.5	6.6	31.9	-40.0	6.2	15.8	50.4	44.2	34.6
8	13.633	38.4	47.6	19.5	6.6	31.9	-40.0	-7.3	1.9	50.4	57.7	48.5
9	13.710	34.9	44.6	19.5	6.6	31.9	-40.0	-10.8	-1.1	40.5	51.3	41.6
10	13.773	37.1	46.7	19.5	6.6	31.9	-40.0	-8.6	1.0	40.5	49.1	39.5
11	14.010	30.1	30.8	19.6	6.6	31.9	-40.0	-15.6	-14.9	29.5	45.1	44.4
12	14.055	30.4	36.1	19.6	6.6	31.9	-40.0	-15.3	-9.6	29.5	44.8	39.1

Calculation:Result[dBuV/m]=Reading[dBuV]+Ant.Fac[dB/m]+Loss(Cable+ATT)[dB]-Gain(AMP)[dB]+Distance factor[dB]

Outside filed strength frequencies

・Fc±7 kHz: 13.553 MHz to 13.567 MHz

・Fc±150 kHz: 13.410 MHz to 13.710 MHz

・Fc±450 kHz: 13.110 MHz to 14.010 MHz

Fc = 13.56 MHz

Limits (30 m)

・13.410 MHz to 13.553 MHz and 13.567 MHz to 13.710 MHz: 50.4 dBuV/m (FCC 15.225(b))

・13.110 MHz to 13.410 MHz and 13.710 MHz to 14.010 MHz: 40.5 dBuV/m (FCC 15.225(c))

・Below 13.110 MHz and Above 14.010 MHz: 29.5 dBuV/m (FCC 15.225(d)and FCC 15.209)

Radiated Emission

UL Japan, Inc.
Shonan EMC Lab. No.1 Semi Anechoic Chamber

Company:	NIDEC SANKYO CORPORATION	Regulation:	FCC Part15 Subpart C 15.225
Equipment:	RFID Module	Test Distance:	3 m
Model:	CLESS001	Date:	January 25, 2021
Sample No.:	DS R-0090001	Temperature:	20 deg.C
Power:	DC 24 V	Humidity:	40 %RH
Mode:	NFC Communication	ENGINEER:	Yasumasa Owaki
EUT axis:	Below 30 MHz, without Tag, Vertical polarization (antenna angle) of the worst case: 90 deg. Above 30 MHz, with Tag		
Remarks:			

Polarity	Frequency [MHz]	Detector	Reading [dBuV]	Ant.Fac. [dB/m]	Loss [dB]	Gain [dB]	Distance Factor [dB]	Result [dBuV/m]	Limit [dBuV/m]	Margin [dB]	Height [cm]	Angle [deg.]	Remark
Hori.	27.12	QP	28.7	20.1	6.9	31.8	-40.0	-16.1	29.5	45.6	-	233	* Limit: 30m
Hori.	40.680	QP	35.1	14.6	7.3	31.8	0.0	25.2	40.0	14.8	263	359	
Hori.	67.800	QP	45.4	6.8	7.4	31.8	0.0	27.8	40.0	12.2	270	18	
Hori.	94.920	QP	42.9	9.2	8.3	31.8	0.0	28.6	43.5	14.9	202	36	
Hori.	352.560	QP	41.4	15.1	6.9	31.8	0.0	31.6	46.0	14.4	100	293	
Hori.	862.969	QP	32.8	21.8	9.5	31.7	0.0	32.4	46.0	13.6	100	262	
Vert.	27.12	QP	29.1	20.1	6.9	31.8	-40.0	-15.7	29.5	45.2	-	237	* Limit: 30m
Vert.	40.680	QP	49.1	14.6	7.3	31.8	0.0	39.2	40.0	**0.8**	100	82	
Vert.	67.800	QP	54.4	6.8	7.4	31.8	0.0	36.8	40.0	3.2	100	20	
Vert.	94.920	QP	49.0	9.2	8.3	31.8	0.0	34.7	43.5	8.8	100	89	
Vert.	108.480	QP	42.5	11.7	8.2	31.8	0.0	30.5	43.5	13.0	100	39	
Vert.	159.93	QP	34.7	15.2	8.9	31.8	0.0	27.0	43.5	16.5	100	58	
Vert.	866.39	QP	34.6	21.8	9.5	31.7	0.0	34.3	46.0	11.7	100	348	

Result = Reading + Ant Factor + Loss (Cable+ATT+ΔAF(above 30MHz)) - Gain(Amprifier) + Distance factor(below 30MHz)
* Other frequency noises omitted in this report were not seen or have enough margin (more than 20 dB).
* Carrier level (Result at 3 m): Hor= 60.9 dBuV/m, Ver= 70.7 dBuV/m

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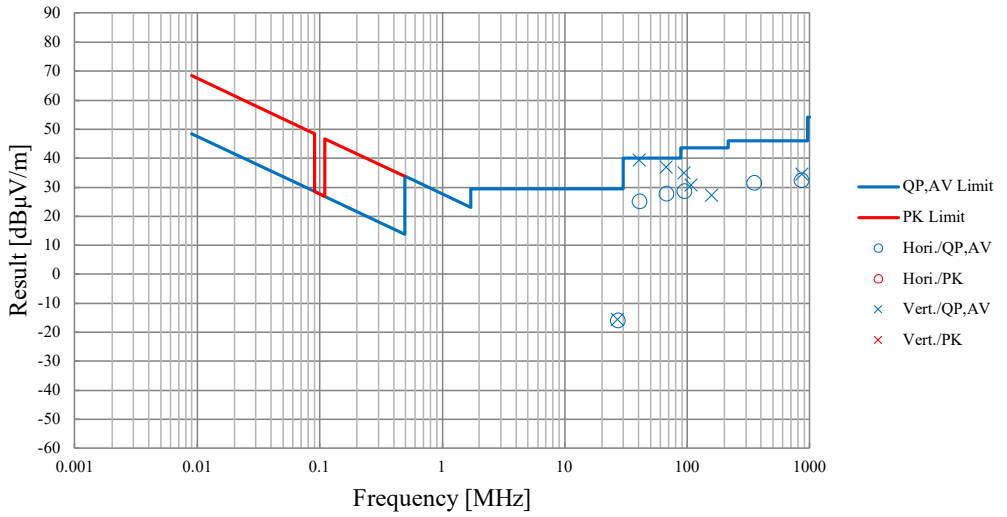
Radiated Emission (Worst mode plot)

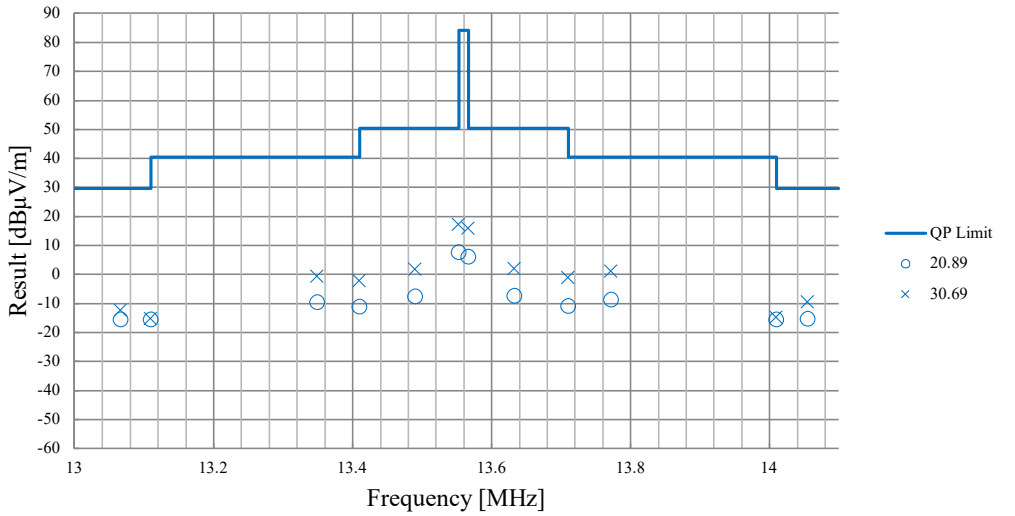
UL Japan, Inc.
Shonan EMC Lab. No.1 Semi Anechoic Chamber

Company:	NIDEC SANKYO CORPORATION	Regulation:	FCC Part15 Subpart C 15.225
Equipment:	RFID Module	Test Distance:	3 m
Model:	CLESS001	Date:	January 25, 2021
Sample No.:	DS R-0090001	Temperature:	20 deg.C
Power:	DC 24 V	Humidity:	40 %RH
Mode:	NFC Communication	ENGINEER:	Yasumasa Owaki
EUT axis:	Below 30 MHz, without Tag, Vertical polarization (antenna angle) of the worst case: 90 deg. Above 30 MHz, with Tag		
Remarks:	These plots data contains sufficient number to show the trend of characteristic features for EUT.		

Spurious emission plot



Within band plot



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Data of Frequency Tolerance

UL Japan, Inc.
Shonan EMC Lab. No.5 Shielded room

Company	NIDEC SANKYO CORPORATION		
Equipment	RFID Module	Regulation	FCC Part15 Subpart C 15.225 (e)
Model	CLESS001	Date	February 9, 2021
Serial No.	DS R-0090001	Temperature	22 deg.C
Power	DC 24V	Humidity	35 %RH
Mode	Transmitting 13.56 MHz	ENGINEER	Toshinori Yamada

Temperature Variation: -20deg.C

Test Conditions	Original Frequency (MHz)	Measure Frequency (MHz)	Frequency Error (MHz)	Frequency tolerance (%)	Limit (%)
startup	13.56	13.559732	-0.000268	-0.00198	0.010
after 2minutes	13.56	13.559669	-0.000331	-0.00244	0.010
after 5minutes	13.56	13.559720	-0.000280	-0.00206	0.010
after 10minutes	13.56	13.559616	-0.000384	-0.00283	0.010

Temperature Variation: -10deg.C

Test Conditions	Original Frequency (MHz)	Measure Frequency (MHz)	Frequency Error (MHz)	Frequency tolerance (%)	Limit (%)
startup	13.56	13.559749	-0.000251	-0.00185	0.010
after 2minutes	13.56	13.559670	-0.000330	-0.00243	0.010
after 5minutes	13.56	13.559751	-0.000249	-0.00184	0.010
after 10minutes	13.56	13.559736	-0.000264	-0.00194	0.010

Temperature Variation: 0deg.C

Test Conditions	Original Frequency (MHz)	Measure Frequency (MHz)	Frequency Error (MHz)	Frequency tolerance (%)	Limit (%)
startup	13.56	13.559808	-0.000192	-0.00142	0.010
after 2minutes	13.56	13.559634	-0.000366	-0.00270	0.010
after 5minutes	13.56	13.559825	-0.000175	-0.00129	0.010
after 10minutes	13.56	13.559725	-0.000275	-0.00203	0.010

Temperature Variation: 10deg.C

Test Conditions	Original Frequency (MHz)	Measure Frequency (MHz)	Frequency Error (MHz)	Frequency tolerance (%)	Limit (%)
startup	13.56	13.559825	-0.000175	-0.00129	0.010
after 2minutes	13.56	13.559846	-0.000154	-0.00114	0.010
after 5minutes	13.56	13.559779	-0.000221	-0.00163	0.010
after 10minutes	13.56	13.559919	-0.000081	-0.00060	0.010

Temperature Variation: 20deg.C

Test Conditions	Original Frequency (MHz)	Measure Frequency (MHz)	Frequency Error (MHz)	Frequency tolerance (%)	Limit (%)
startup	13.56	13.559799	-0.000201	-0.00148	0.010
after 2minutes	13.56	13.559660	-0.000340	-0.00251	0.010
after 5minutes	13.56	13.559903	-0.000097	-0.00072	0.010
after 10minutes	13.56	13.559679	-0.000321	-0.00237	0.010

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Data of Frequency Tolerance

Temperature Variation: 30deg.C

Test Conditions	Original Frequency (MHz)	Measure Frequency (MHz)	Frequency Error (MHz)	Frequency tolerance (%)	Limit (%)
startup	13.56	13.559807	-0.000193	-0.00142	0.010
after 2minutes	13.56	13.559754	-0.000246	-0.00181	0.010
after 5minutes	13.56	13.559804	-0.000196	-0.00145	0.010
after 10minutes	13.56	13.559790	-0.000210	-0.00155	0.010

Temperature Variation: 40deg.C

Test Conditions	Original Frequency (MHz)	Measure Frequency (MHz)	Frequency Error (MHz)	Frequency tolerance (%)	Limit (%)
startup	13.56	13.559814	-0.000186	-0.00137	0.010
after 2minutes	13.56	13.559748	-0.000252	-0.00186	0.010
after 5minutes	13.56	13.559777	-0.000223	-0.00164	0.010
after 10minutes	13.56	13.559834	-0.000166	-0.00123	0.010

Temperature Variation: 50deg.C

Test Conditions	Original Frequency (MHz)	Measure Frequency (MHz)	Frequency Error (MHz)	Frequency tolerance (%)	Limit (%)
startup	13.56	13.559744	-0.000256	-0.00189	0.010
after 2minutes	13.56	13.559801	-0.000199	-0.00147	0.010
after 5minutes	13.56	13.559901	-0.000099	-0.00073	0.010
after 10minutes	13.56	13.559901	-0.000099	-0.00073	0.010

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Data of Frequency Tolerance

UL Japan, Inc.
Shonan EMC Lab. No.5 Shielded room

Company	NIDEC SANKYO CORPORATION		
Equipment	RFID Module	Regulation	FCC Part15 Subpart C 15.225 (e)
Model	CLESS001	Date	February 9, 2021
Serial No.	DS R-0090001	Temperature	22 deg.C
Power	DC 24V	Humidity	35 %RH
Mode	Transmitting 13.56 MHz	ENGINEER	Toshinori Yamada

Voltage Variation: DC 20.4 V
Temperature Variation: 20deg.C

Test Conditions	Original Frequency (MHz)	Measure Frequency (MHz)	Frequency Error (MHz)	Frequency tolerance (%)	Limit (%)
startup	13.56	13.559772	-0.000228	-0.00168	0.010
after 2minutes	13.56	13.559761	-0.000239	-0.00177	0.010
after 5minutes	13.56	13.559805	-0.000195	-0.00144	0.010
after 10minutes	13.56	13.559866	-0.000134	-0.00099	0.010

Voltage Variation: DC 27.6 V
Temperature Variation: 20deg.C

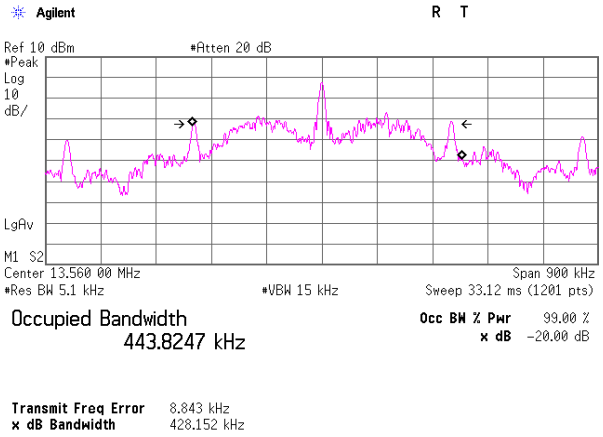
Test Conditions	Original Frequency (MHz)	Measure Frequency (MHz)	Frequency Error (MHz)	Frequency tolerance (%)	Limit (%)
startup	13.56	13.559749	-0.000251	-0.00185	0.010
after 2minutes	13.56	13.559965	-0.000035	-0.00026	0.010
after 5minutes	13.56	13.559918	-0.000082	-0.00061	0.010
after 10minutes	13.56	13.559813	-0.000187	-0.00138	0.010

20dB bandwidth & 99% Occupied bandwidth: FCC 15.215 / RSS-Gen

UL Japan, Inc.
Shonan EMC Lab. No.2 Shielded Room

Company:	NIDEC SANKYO CORPORATION	Regulation:	FCC Part15 Subpart C 15.215
Equipment:	RFID Module		
Model:	CLESS001	Date:	February 9, 2021
Sample No.:	DS R-0090001	Temperature:	22 deg.C
Power:	DC 24 V	Humidity:	35 %RH
Mode:	NFC Communication	ENGINEER:	Toshinori Yamada

20dB Bandwidth: 428.152 kHz
99% Occupied Bandwidth: 443.825 kHz



APPENDIX 3

Test Instruments

EMI test equipment

Test Name	Local ID	LIMS ID	Description	Manufacturer	Model	Serial	Last Calibration Date	Calibration Interval (Month)
CE	KAT3-12	144896	Attenuator	JFW IND. INC.	50HF-003N	-	2020/07/16	12
CE	KJM-10	146454	Measure	KOMELON	KMC-36	-	-	-
CE	SCC-B12/B13/SRSE-02	144969	Coaxial Cable&RF Selector	Suhner/Suhner/TOYO	RG223U/141PE/NS4906	-/0901-270(RF Selector)	2020/04/17	12
CE	SLS-03	145540	LISN	Rohde & Schwarz	ENV216	100513	2020/02/19	12
CE	SLS-04	145541	LISN	Rohde & Schwarz	ENV216	100514	2020/02/19	12
CE	SOS-22	191839	Humidity Indicator	CUSTOM. Inc	CTH-201	-	2020/10/01	12
CE	STM-03	146188	Terminator	TME	CT-01 BP	-	2020/12/07	12
CE	STR-07	146209	Receiver, EMI	Rohde & Schwarz	ESU26	100484	2020/09/07	12
CE	STS-02	145793	Digital Hitester	HIOKI E.E. CORPORATION	3805-50	80997819	2020/04/09	12
CE,RE	COTS-SEMI-5	170932	EMI Software	TSJ (Techno Science Japan)	TEPTO-DV3(RE,CE,ME,PE)	-	-	-
RE	KAT6-04	144899	Attenuator	Inmet	18N-6dB	-	2020/12/10	12
RE	KJM-09	145929	Measure	KOMELON	KMC-36	-	-	-
RE	SAEC-01(NSA)	145597	Semi-Anechoic Chamber	TDK	SAEC-01(NSA)	1	2020/04/08	12
RE	SAF-01	145003	Pre Amplifier	SONOMA	310N	290211	2020/02/19	12
RE	SAT3-09	144959	Attenuator	JFW	50HF-003N	-	2020/08/18	12
RE	SAT6-15	167096	Attenuator	JFW	50HF-006N	-	2020/02/21	12
RE	SBA-01	145161	Biconical Antenna	Schwarzbeck Mess - Elektronik	BBA9106	91032664	2020/04/04	12
RE	SCC-A1/A3/A5/A7/A8/A13/SRSE-01	144967	Coaxial Cable&RF Selector	Fujikura/Fujikura/Suhner/Suhner/Suhner/Suhner/TOYO	8D2W/12DSFA/141PE/141PE/141PE/141PE/NS4906	-/0901-269(RF Selector)	2020/04/12	12
RE	SCC-A2/A4/A6/A7/A8/A13/SRSE-01	144968	Coaxial Cable&RF Selector	Fujikura/Fujikura/Suhner/Suhner/Suhner/Suhner/TOYO	8D2W/12DSFA/141PE/141PE/141PE/141PE/NS4906	-/0901-269(RF Selector)	2020/04/12	12
RE	SCC-M1	194601	Coaxial Cable	Fjikura	5D-2W	-	2020/12/10	12
RE	SLA-05	145527	Logperiodic Antenna	Schwarzbeck Mess - Elektronik	VUSLP9111B	193	2020/04/04	12
RE	SLP-02	145536	Loop Antenna	Rohde & Schwarz	HFH2-Z2	100218	2020/04/15	12
RE	SOS-20	191837	Humidity Indicator	CUSTOM. Inc	CTH-201	-	2020/09/28	12
RE	STR-01	145790	Test Receiver	Rohde & Schwarz	ESU40	100093	2020/04/24	12
RE	STS-01	145792	Digital Hitester	HIOKI E.E. CORPORATION	3805-50	80997812	2020/10/19	12
TF	SCH-01	145200	Temperature and Humidity Chamber	Espec	PL-1KT	14020837	2020/04/02	12
TF	SOS-27	191845	Humidity Indicator	CUSTOM. Inc	CTH-201	-	2020/09/29	12
TF	SSA-02	145800	Spectrum Analyzer	Keysight Technologies Inc	E4448A	MY48250106	2020/04/16	12
TF	SSCA-01	146178	Search coil	Langer	RF-R 400-1	02-0634	-	-
TF	STS-05	146212	Digital Hitester	HIOKI E.E. CORPORATION	3805-50	80997828	2020/10/19	12

*Hyphens for Last Calibration Date and Cal Int (month) are instruments that Calibration is not required (e.g. software), or instruments checked in advance before use.

The expiration date of the calibration is the end of the expired month.
As for some calibrations performed after the tested dates , those test equipment have been controlled by means of an unbroken chains of calibrations.

All equipment is calibrated with valid calibrations . Each measurement data is traceable to the national or international standards
Test Item:
CE: Conducted emission,
RE: Radiated emission,
TF: Test Fixture

End of Report